



Applicant: Wallace T.Y. Tang

Art Unit : 1763

Serial No.: 09/134,147

Examiner: Trung Dang

Filed

: August 14, 1998

Title

: IN-SITU REAL-TIME MONITORING TECHNIQUE AND APPARATUS FOR

DETECTION OF THIN FILMS DURING CHEMICAL/MECHANICAL

POLISHING PLANARIZATION

Commissioner for Patents Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Applicant submits copies of the references listed on the attached form PTO-1449.

This filing is being made with the filing of a Request for Continued Examination. No fee

is required.

Respectfully submitted,

12/3/02 Date:

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, Washington, D.C. 20231.

December 3, 2002		
Date of Deposit	\supset	
Signature		

Typed or Printed Name of Person Signing Certificate

Nikia M. Mc Nillion